

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Yuji YOSHIKAWA, et al.

SERIAL NO: New Application

GAU:

FILED: Herewith

EXAMINER:

FOR: ANTIREFLECTION FILM AND MAKING METHOD

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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DOCKET NO: 242919US0

Sheet 1 of 1

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STATEMENT OF RELEVANCY

Reference AL (JP 2800258) on Form PTO- 1449:

This reference is discussed in the specification.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242919US0		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yuji YOSHIKAWA, et al.			
				FILING DATE Herewith		GROUP	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
	AA	6-11601,	01/21/94	Japan (with English Abstract)		X	
	AB	7-60856 -	03/07/95	Japan (with English Abstract)		X	
	AC	2000-284235	10/13/00	Japan (with English Abstract)		X	
	AD	2001-293813	10/23/01	Japan (with English Abstract)		X	
	AE	3031571	02/10/00	Japan (with English Abstract)		X	
	AF	2000-204301	07/25/00	Japan (with English Abstract)		X	
	AG	2000-6402	01/11/00	Japan (with English Abstract)		X	
	AH	2000-47004	02/18/00	Japan (with English Abstract)		X	
	AI	2000-143924	05/26/00	Japan (with English Abstract)		X	
	AJ	2000-266908	09/29/00	Japan (with English Abstract)		X	
	AK	2000-329903	11/30/00	Japan (with English Abstract)		X	
	AL	2001-164117	06/19/01	Japan (with English Abstract)		X	
	AM	2800258	07/10/98	Japan		X	
	AN	10-147740	06/02/98	Japan (with English Abstract)		X	
	AO	8-313704	11/29/96	Japan (with English Abstract)		X	
	AP	2001-264508	09/26/01	Japan (with English Abstract)		X	
	AQ	2002-22905	01/23/02	Japan (with English Abstract)		X	
	AR	2002-53804	02/19/02	Japan (with English Abstract)		X	
	AS	2002-53805	02/19/02	Japan (with English Abstract)		X	
	AT	2002-69426	03/08/02	Japan (with English Abstract)		X	
	AU	2001-316604	11/16/01	Japan (with English Abstract)		X	
	AV	2001-31891	02/06/01	Japan (with English Abstract)		X	
	AW	2000-79600	03/21/00	Japan (with English Abstract)		X	
	AX	2001-163906	06/19/01	Japan (with English Abstract)		X	
	AY	2000-17099	01/18/00	Japan (with English Abstract)		X	
	AZ	2001-233611	08/28/01	Japan (with English Abstract)		X	
	BA	2002-79616	03/19/02	Japan (with English Abstract)		X	
	BB	9-227169	09/02/97	Japan (with English Abstract)		X	
	BC	3225859	08/31/01	Japan (with English Abstract)		X	
	BD	2001-315285	11/13/01	Japan (with English Abstract)		X	
	BE				<input type="checkbox"/> Additional References sheet(s) attached		
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							